

<b>Notice of References Cited</b>		Application/Control No. 10/738,337	Applicant(s)/Patent Under Reexamination OHSAWA, KENRO	
		Examiner Javid A. Amini	Art Unit 2628	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,005,945 A	04-1991	van de Ven, Johannes C.	359/456
*	B	US-5,504,598 A	04-1996	Sprague et al.	349/57
*	C	US-5,534,949 A	07-1996	Baron, Peter C.	348/742
*	D	US-6,219,011 B1	04-2001	Aloni et al.	345/1.3
*	E	US-6,262,744 B1	07-2001	Carrein, Geert	345/604
*	F	US-2001/0015714 A1	08-2001	Yamazaki et al.	345/92
*	G	US-6,342,929 B1	01-2002	Hirata et al.	348/779
*	H	US-6,377,230 B1	04-2002	Yamazaki et al.	345/7
*	I	US-2002/0154089 A1	10-2002	Yamazaki et al.	345/103
*	J	US-6,590,562 B2	07-2003	Yamazaki et al.	345/103
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.